

Features

- Split Gate Trench MOSFET technology
- Excellent package for heat dissipation
- High density cell design for low $R_{DS(ON)}$



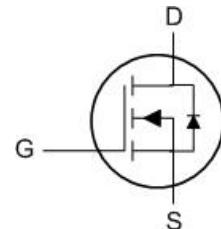
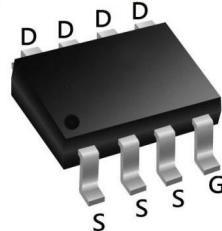
Product Summary

BVDSS	RDS(on)	ID
100V	61mΩ	15A

Applications

- DC-DC Converters
- Power management functions
- Synchronous-rectification applications

GCD, 'D]b'7cbZ[i fU]cb'



Absolute Maximum Ratings

Symbol	Parameter	Rating	Units
V_{DS}	Drain-Source Voltage	100	V
V_{GS}	Gate-Source Voltage	± 20	V
$I_D @ T_C = 25^\circ C$	Continuous Drain Current, $V_{GS} @ 10V^{1.6}$	15	A
$I_D @ T_C = 100^\circ C$	Continuous Drain Current, $V_{GS} @ 10V^{1.6}$	10.7	A
I_{DM}	Pulsed Drain Current ²	80	A
EAS	Single Pulse Avalanche Energy ³	22	mJ
I_{AS}	Avalanche Current	---	A
$P_D @ T_C = 25^\circ C$	Total Power Dissipation ⁴	46	W
T_{STG}	Storage Temperature Range	-55 to 150	°C
T_J	Operating Junction Temperature Range	-55 to 150	°C

Thermal Data

Symbol	Parameter	Typ.	Max.	Unit
$R_{\theta JA}$	Thermal Resistance Junction-Ambient ¹	---	---	°C/W
$R_{\theta JC}$	Thermal Resistance Junction-Case ¹	---	2.7	°C/W

Electrical Characteristics ($T_J=25^\circ\text{C}$, unless otherwise noted)

Symbol	Parameter	Conditions	Min.	Typ.	Max.	Unit
BV_{DSS}	Drain-Source Breakdown Voltage	$\text{V}_{\text{GS}}=0\text{V}$, $\text{I}_D=250\mu\text{A}$	100	---	---	V
$\Delta \text{BV}_{\text{DSS}}/\Delta T_J$	BV_{DSS} Temperature Coefficient	Reference to 25°C , $\text{I}_D=1\text{mA}$	---	---	---	$\text{V}/^\circ\text{C}$
$R_{\text{DS}(\text{ON})}$	Static Drain-Source On-Resistance ²	$\text{V}_{\text{GS}}=10\text{V}$, $\text{I}_D=5\text{A}$	---	61	75	$\text{m}\Omega$
		$\text{V}_{\text{GS}}=4.5\text{V}$, $\text{I}_D=4\text{A}$	---	77	100	
$\text{V}_{\text{GS}(\text{th})}$	Gate Threshold Voltage	$\text{V}_{\text{GS}}=\text{V}_{\text{DS}}$, $\text{I}_D=250\mu\text{A}$	1.3	1.8	2.3	V
$\Delta \text{V}_{\text{GS}(\text{th})}$	$\text{V}_{\text{GS}(\text{th})}$ Temperature Coefficient		---	---	---	$\text{mV}/^\circ\text{C}$
I_{DSS}	Drain-Source Leakage Current	$\text{V}_{\text{DS}}=100\text{V}$, $\text{V}_{\text{GS}}=0\text{V}$, $T_J=25^\circ\text{C}$	---	---	1	uA
		$\text{V}_{\text{DS}}=100\text{V}$, $\text{V}_{\text{GS}}=0\text{V}$, $T_J=100^\circ\text{C}$	---	---	100	
I_{GSS}	Gate-Source Leakage Current	$\text{V}_{\text{GS}}=\pm 20\text{V}$, $\text{V}_{\text{DS}}=0\text{V}$	---	---	± 100	nA
g_{fs}	Forward Transconductance	$\text{V}_{\text{DS}}=10\text{V}$, $\text{I}_D=5\text{A}$	---	---	---	S
R_g	Gate Resistance	$\text{V}_{\text{DS}}=0\text{V}$, $\text{V}_{\text{GS}}=0\text{V}$, $f=1\text{MHz}$	---	---	---	Ω
Q_g	Total Gate Charge	$\text{V}_{\text{DS}}=50\text{V}$, $\text{V}_{\text{GS}}=10\text{V}$, $\text{I}_D=10\text{A}$	---	3.7	---	nC
Q_{gs}	Gate-Source Charge		---	0.8	---	
Q_{gd}	Gate-Drain Charge		---	1	---	
$\text{T}_{\text{d(on)}}$	Turn-On Delay Time	$\text{V}_{\text{GS}}=10\text{V}$, $\text{VDD}=50\text{V}$, $\text{RG}=3\Omega$, $\text{ID}=10\text{A}$	---	8	---	ns
T_r	Rise Time		---	16	---	
$\text{T}_{\text{d(off)}}$	Turn-Off Delay Time		---	17	---	
T_f	Fall Time		---	14	---	
C_{iss}	Input Capacitance	$\text{V}_{\text{DS}}=50\text{V}$, $\text{V}_{\text{GS}}=0\text{V}$, $f=1\text{MHz}$	---	228	---	pF
C_{oss}	Output Capacitance		---	58	---	
C_{rss}	Reverse Transfer Capacitance		---	1.9	---	

Diode Characteristics

Symbol	Parameter	Conditions	Min.	Typ.	Max.	Unit
I_s	Continuous Source Current ^{1,4}	$\text{V}_{\text{G}}=\text{V}_{\text{D}}=0\text{V}$, Force Current	---	---	15	A
V_{SD}	Diode Forward Voltage ²	$\text{V}_{\text{GS}}=0\text{V}$, $\text{I}_s=20\text{A}$, $T_J=25^\circ\text{C}$	---	---	1.2	V
t_{rr}	Reverse Recovery Time	$\text{I}_{\text{F}}=10\text{A}$, $\text{di/dt}=100\text{A}/\mu\text{s}$, $T_J=25^\circ\text{C}$	---	22	---	nS
			---	18	---	nC

Note :

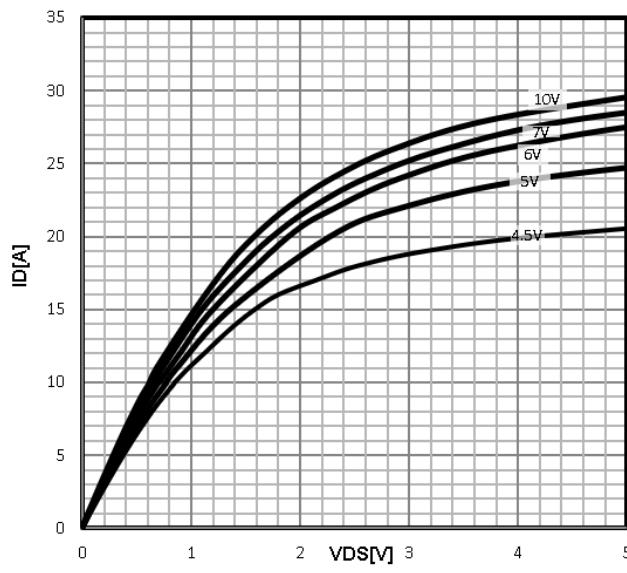
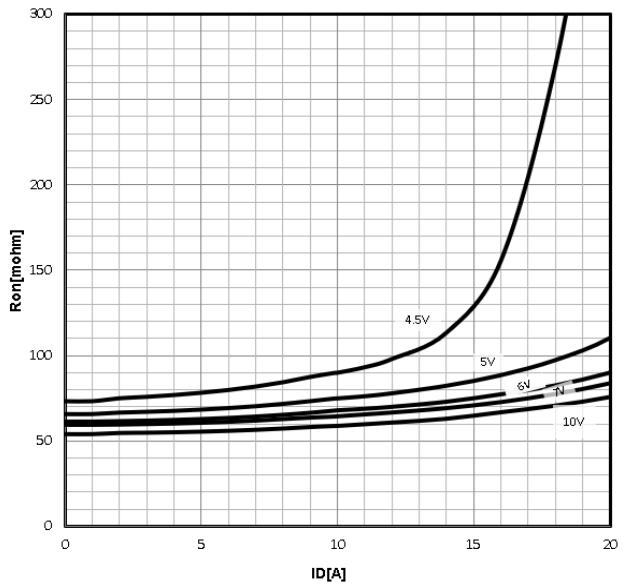
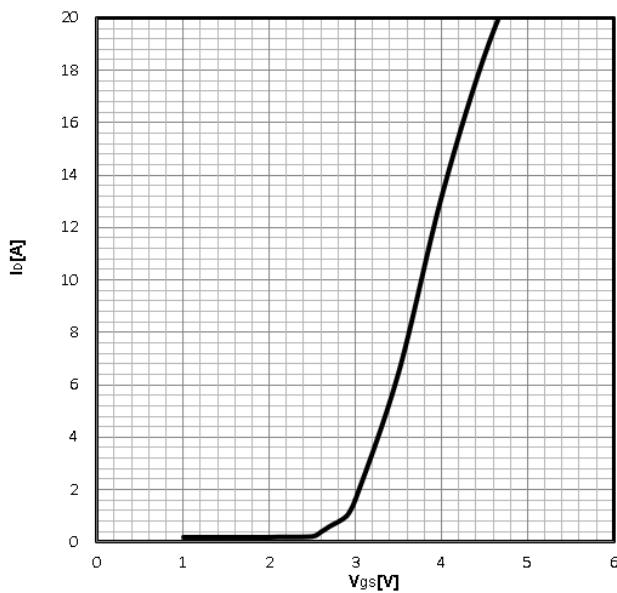
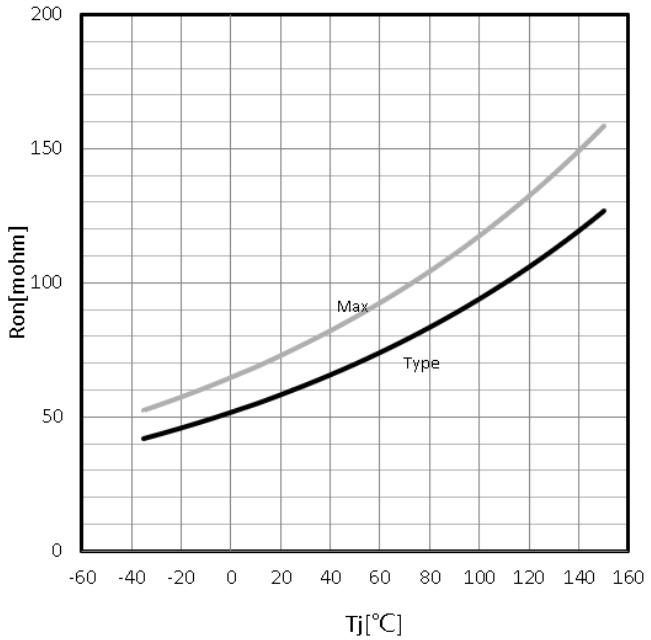
 The data is tested by a surface-mounted diode on a 1 inch² FR-4 board with 2OZ copper.

The data is tested by a pulsed pulse width 300us duty cycle 2%.

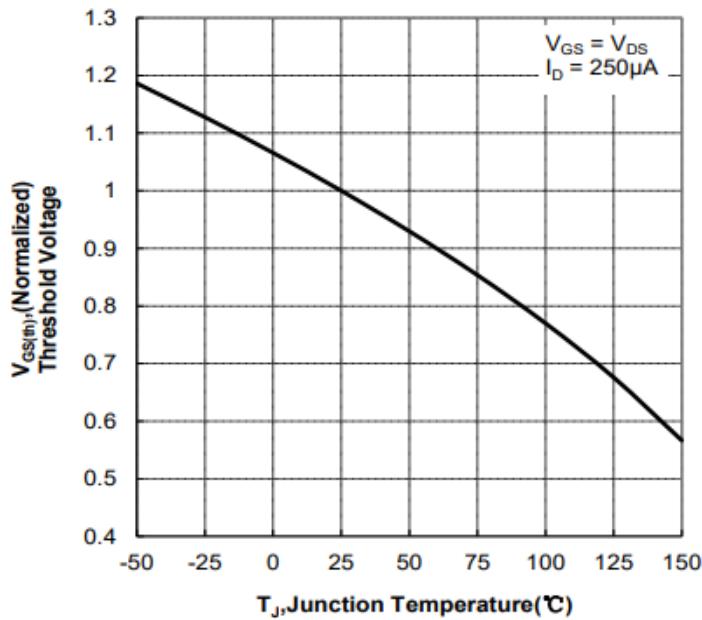
 The EAS data shows Max. rating . The test condition is $\text{VR}_{\text{MAG}}>0$, $\text{VDD}=50\text{V}$, $\text{VGS}=10\text{V}$, $L=5\text{mH}$.

The power dissipation is limited by 150 °C junction temperature

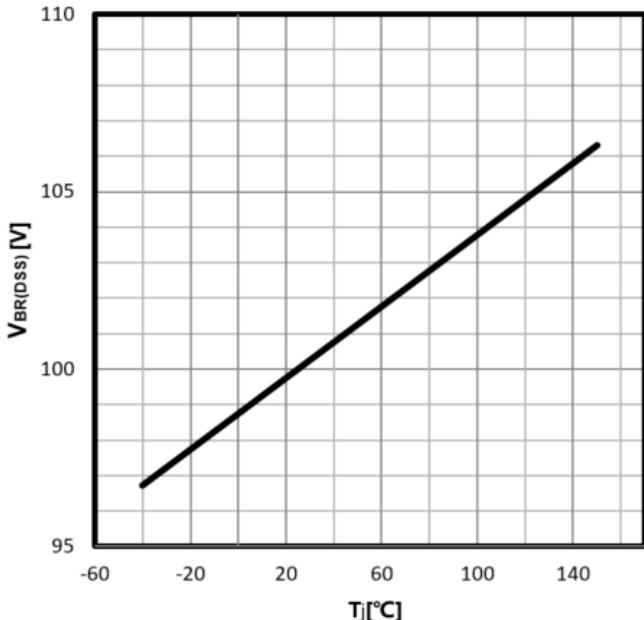
 The data is theoretically the same as A_{DSS} and A_{DM} . In real applications, it should be limited by total power dissipation.

Characteristics Curve:
Typ. output characteristics
 $I_D = f(V_{DS})$

Typ. drain-source on resistance
 $R_{DS(on)} = f(I_D)$

Typ. transfer characteristics
 $I_D = f(V_{GS})$

Drain-source on-state resistance
 $R_{DS(on)} = f(T_j); I_D = 5A; V_{GS} = 10V$


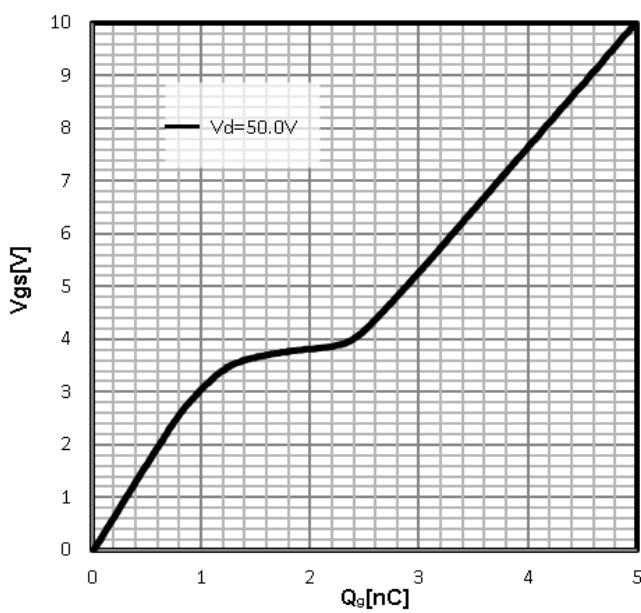
Gate Threshold Voltage
 $V_{TH}=f(T_j)$; $I_D=250\mu A$



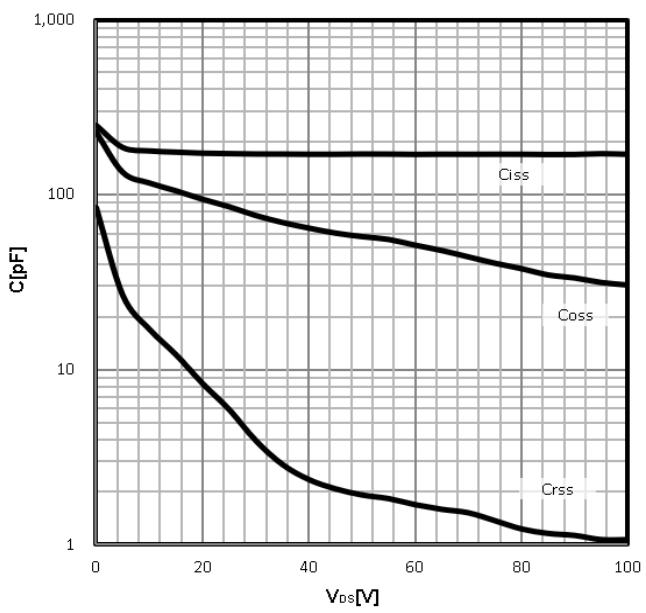
Drain-source breakdown voltage
 $V_{BR(DSS)}=f(T_j)$; $I_D=250\mu A$

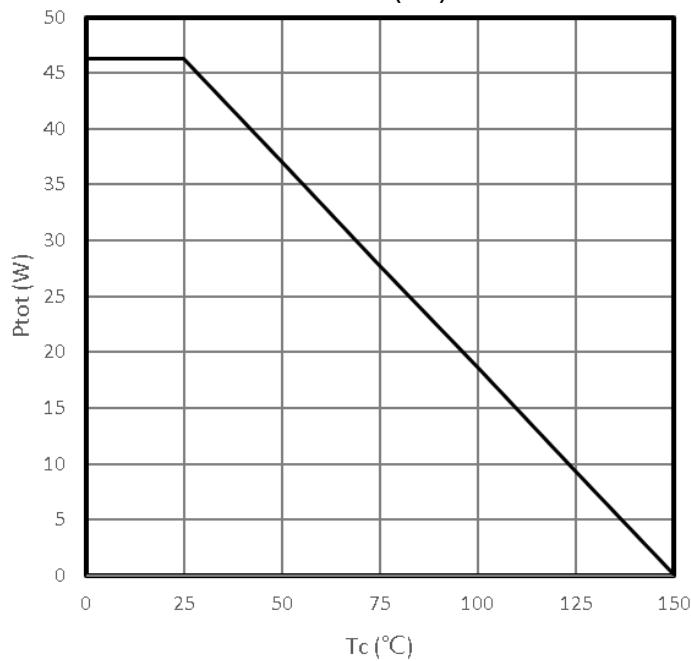
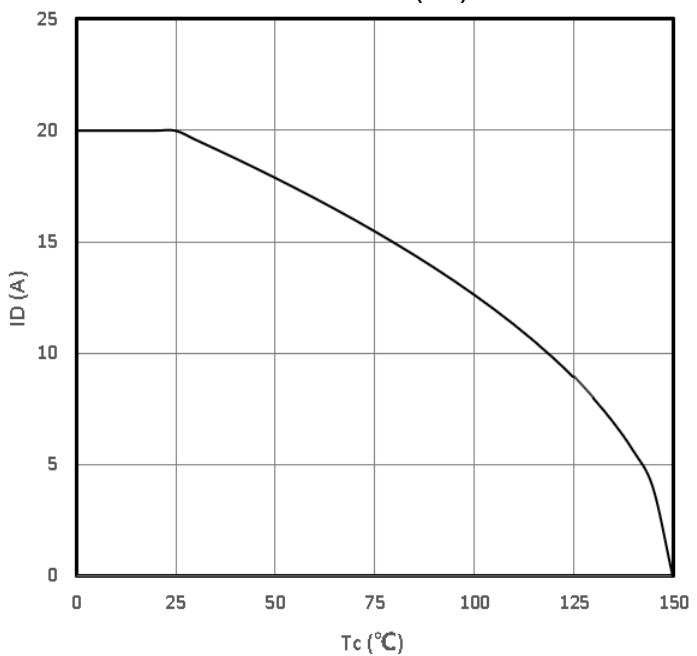
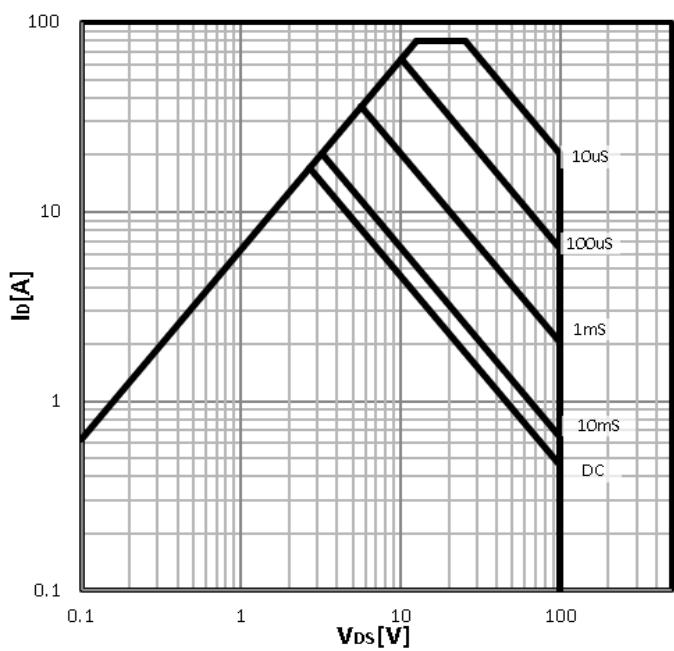
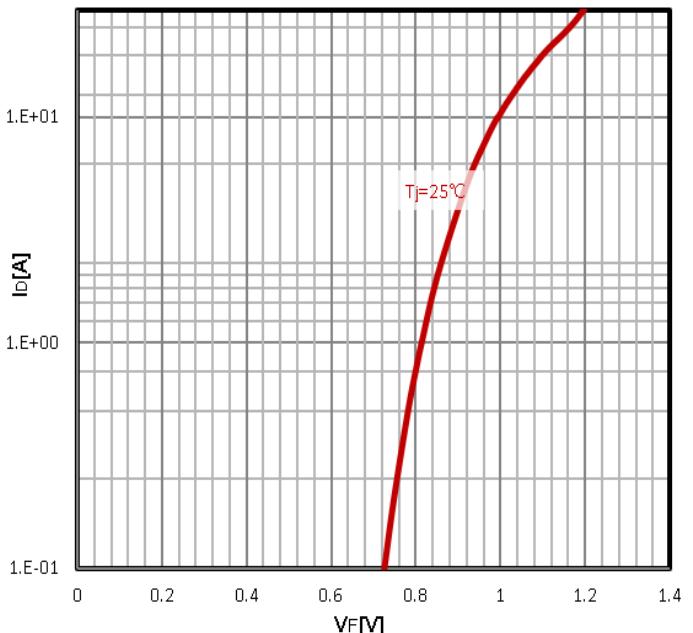


Typ. gate charge
 $V_{GS}=f(Q_g)$; $I_D=10A$



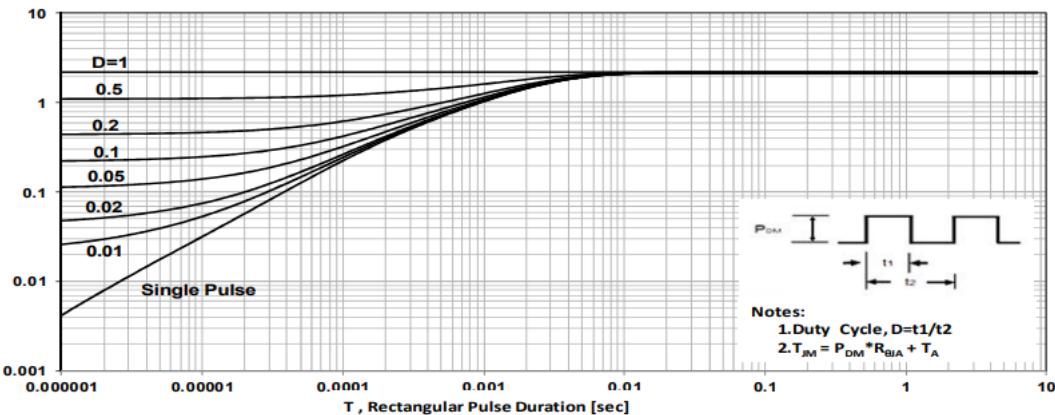
Typ. capacitances
 $C=f(V_{DS})$; $V_{GS}=0V$; $f=1MHz$

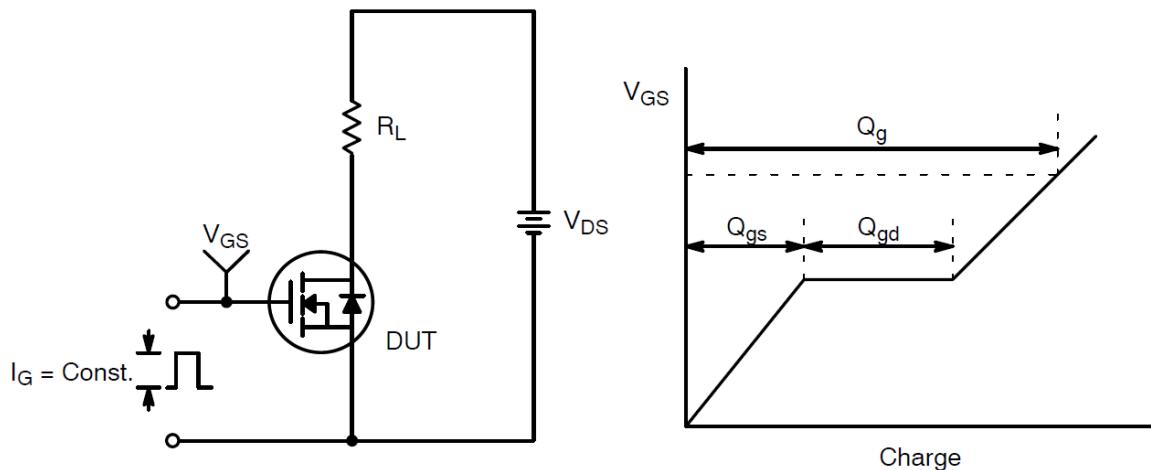
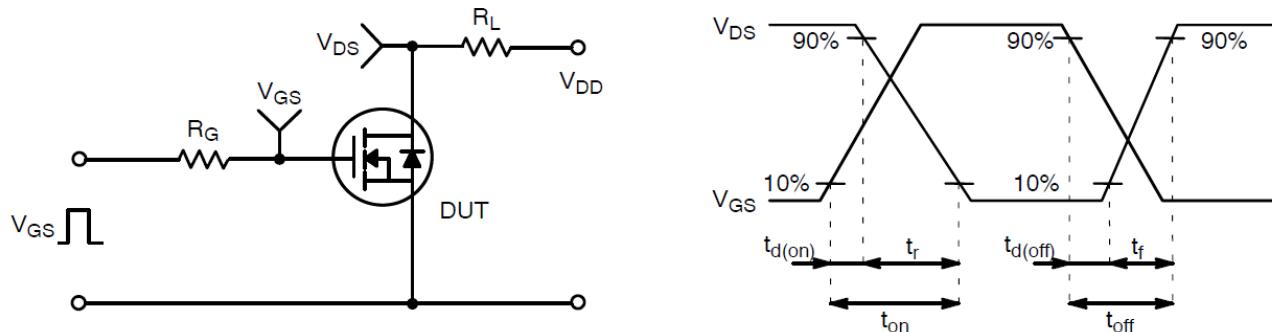
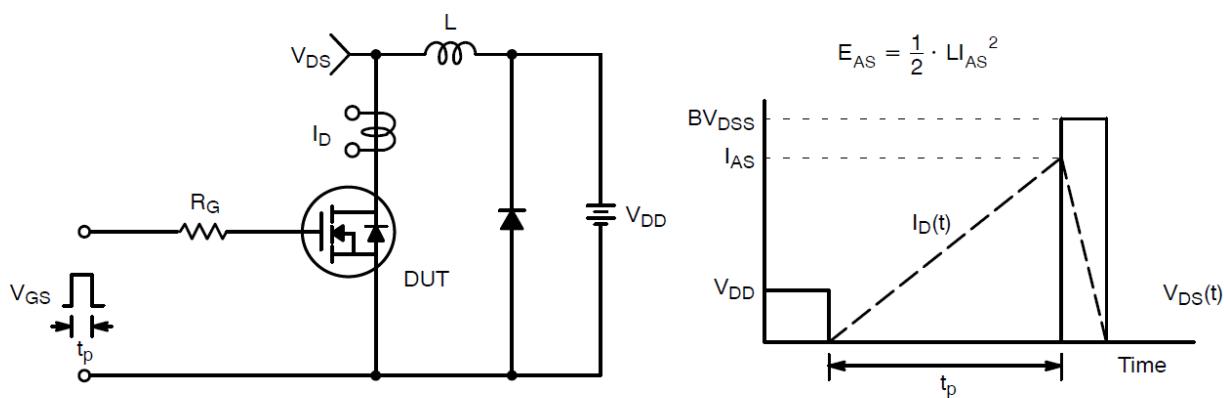


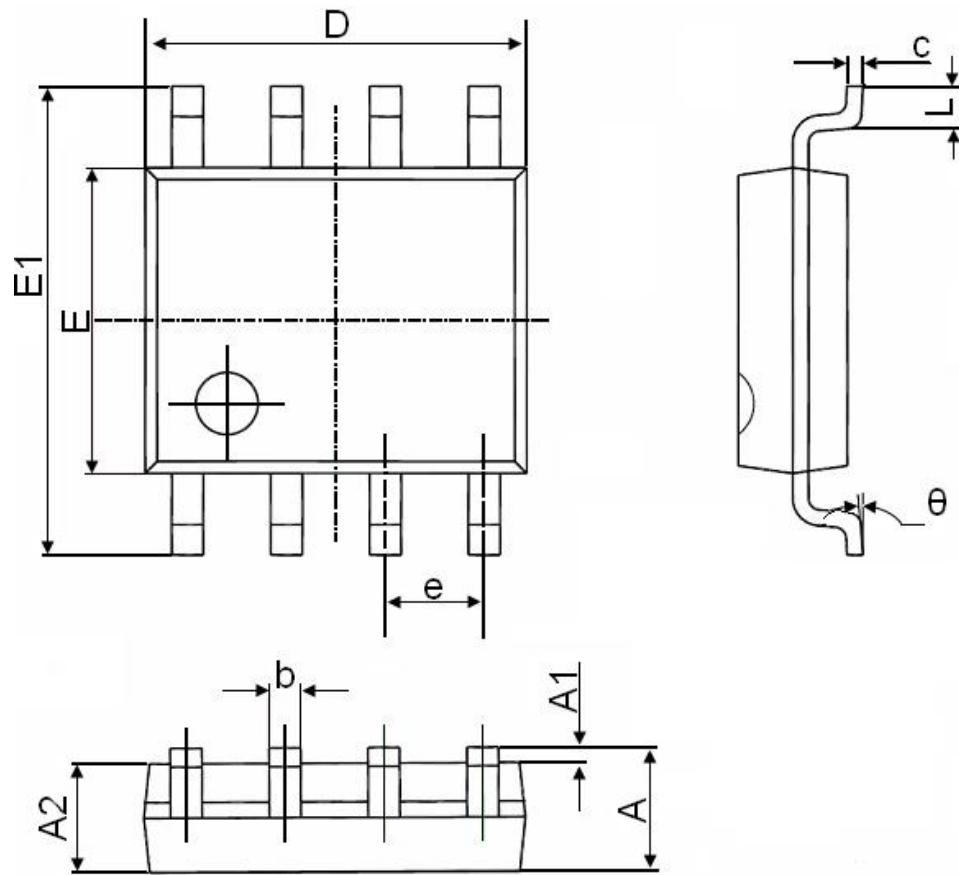
Power Dissipation
 $P_{tot}=f(T_c)$

Maximum Drain Current
 $I_D=f(T_c)$

Safe operating area
 $I_D=f(V_{DS})$

Body Diode Forward Voltage Variation
 $I_F=f(V_{GS})$


Max. transient thermal impedance

$$Z_{thJC} = f(t_p)$$



Test Circuit and Waveform:

Gate Charge Test Circuit & Waveform

Resistive Switching Test Circuit & Waveforms

Unclamped Inductive Switching Test Circuit & Waveforms

SOP-8 Package Information


Symbol	Dimensions In Millimeters		Dimensions In Inches	
	Min.	Max.	Min.	Max.
A	1.350	1.750	0.053	0.069
A1	0.100	0.250	0.004	0.010
A2	1.350	1.550	0.053	0.061
b	0.330	0.510	0.013	0.020
c	0.170	0.250	0.006	0.010
D	4.700	5.100	0.185	0.200
E	3.800	4.000	0.150	0.157
E1	5.800	6.200	0.228	0.244
e	1.270(BSC)		0.050(BSC)	
L	0.400	1.270	0.016	0.050
θ	0°	8°	0°	8°